

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Patty Docket No. LAM1P136/P0602	Application No. 09/539,313
	Applicant: HUANG et al. Filing Date March 30, 2000	Group 2755

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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

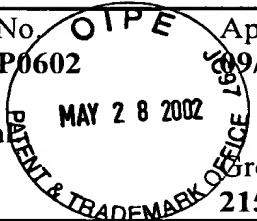
Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
<i>De</i>	O	U.S. Patent Application No. 09/539,312, filed March 30, 2000, entitled: "Integrated Full Wavelength Spectrometer for Wafer Processing"
	P	
	Q	
Examiner <i>David England</i>	Date Considered <i>3/31/03</i>	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. LAM1P136/P0602 Applicant: HUANG et al Filing Date 03/30/00	Application No.: 209/539,313 Group 2152
		

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
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Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
<i>DE</i>	J	99 08168 A	18/02/99	WIPO	G05B	23/02	Yes	
<i>DE</i>	K	2 692 701	24/12/93	France	G06F	15/46		No
<i>DE</i>	L	0552 873 A1	28/07/93	EPO	G06F	13/40	Yes	
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
<i>DE</i>	O	International Search Report, date mailed April 19, 2002
<i>DE</i>	P	Kang B. Lee and Richard D. Schneeman, "Internet-Based Distributed Measurement and Control Applications", IEEE Instrumentation & Measurement Magazine, June 1999, pg. 23-27
	Q	
Examiner <i>David England</i>		Date Considered <i>3/31/03</i>

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